L Number	Hits	Search Text	DB	Time stamp
1	3	(("5644578") or ("5568437") or ("5659551")).PN.	USPAT	2004/06/26 16:56
2	54	"5568437"	USPAT	2004/06/26 16:58
3	1043897	integrated circuit with built-in self-test	USPAT;	2004/06/26 16:58
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
4	8291826	external testing device	USPAT;	2004/06/26 16:59
4	0231020	Continuit County active	US-PGPUB;	200 17 007 20 10.33
			EPO; JPO;	
			DERWENT;	
	600350	(integrated singuit with built in calf test) and (automat testing	IBM_TDB	2004/06/26 47:04
5	699359	(integrated circuit with built-in self-test) and (external testing	USPAT;	2004/06/26 17:01
		device)	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
6	469523	evaluat\$3 and (test result\$1)	USPAT;	2004/06/26 17:02
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
7	5596704	reading out result\$1 and (external testing device)	USPAT;	2004/06/26 17:05
			US-PGPUB;	,,
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
8	412642	(evaluat\$3 and (test result\$1)) and (reading out result\$1 and	USPAT;	2004/06/26 17:07
	112012	(external testing device))	US-PGPUB;	2004/00/26 17.07
		(external testing device))		
			EPO; JPO;	
			DERWENT;	
9	06055	(/inhomenhod singuith with built in out the state of the	IBM_TDB	2004/25/25
	86855	((integrated circuit with built-in self-test) and (external testing	USPAT;	2004/06/26 17:10
		device)) and ((evaluat\$3 and (test result\$1)) and (reading out	US-PGPUB;	
		result\$1 and (external testing device)))	EPO; JPO;	
			DERWENT;	
			IBM_TDB	
10	4891759	test result memory	USPAT;	2004/06/26 17:10
i			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
11	86855	(((integrated circuit with built-in self-test) and (external testing	USPAT;	2004/06/26 17:12
		device)) and ((evaluat\$3 and (test result\$1)) and (reading out	US-PGPUB;	, ,
		result\$1 and (external testing device)))) and (test result memory)	EPO; JPO;	
		,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	DERWENT;	
			IBM_TDB	
12	10276977	self-test control device	USPAT;	2004/06/26 17:13
			US-PGPUB;	200 1,00,20 17.13
l			EPO; JPO;	
			DERWENT;	
13	85250	((((integrated circuit with built in self-test) and (automat to the	IBM_TDB	2004/06/26 47 40
13	03230	((((integrated circuit with built-in self-test) and (external testing	USPAT;	2004/06/26 17:18
l		device)) and ((evaluat\$3 and (test result\$1)) and (reading out	US-PGPUB;	
		result\$1 and (external testing device)))) and (test result memory))	EPO; JPO;	
ļ		and (self-test control device)	DERWENT;	
			IBM_TDB	
14	4889	714/733.ccls. or 714/734.ccls. or 714/724.ccls. or 714/30.ccls. or	USPAT;	2004/06/26 17:20
		714/726.ccls.	US-PGPUB;	,
			EPO; JPO;	
			DERWENT;	

15	582	device)) and ((evaluat\$3 and (test result\$1)) and (reading out result\$1 and (external testing device)))) and (test result memory))	USPAT; US-PGPUB; EPO; JPO;	2004/06/26 17:22
		and (self-test control device)) and (714/733.ccls. or 714/734.ccls.	DERWENT;	
16	848447	or 714/724.cds. or 714/30.cds. or 714/726.cds.)	IBM_TDB	2004/06/26 17:22
10	040447	enorşi	USPAT; US-PGPUB;	2004/06/26 17:22
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
17	303	((((((integrated circuit with built-in self-test) and (external testing	USPAT;	2004/06/26 17:23
		device)) and ((evaluat\$3 and (test result\$1)) and (reading out	US-PGPUB;	
		result\$1 and (external testing device)))) and (test result memory)) and (self-test control device)) and (714/733.ccls. or 714/734.ccls.	EPO; JPO;	
		or 714/724.ccls. or 714/30.ccls. or 714/726.ccls. )) and error\$1	DERWENT; IBM_TDB	
18	3340	"BIST" or "built-in self-test"	USPAT;	2004/06/26 17:23
			US-PGPUB;	200 1, 00, 20 27 123
			EPO; JPO;	
			DERWENT;	
19	88	((((((integrated circuit with built is self test) and (sytemal testical	IBM_TDB	2004/06/26 47:24
17	00	(((((((integrated circuit with built-in self-test) and (external testing device)) and ((evaluat\$3 and (test result\$1)) and (reading out	USPAT; US-PGPUB;	2004/06/26 17:24
		result\$1 and (external testing device)))) and (test result memory))	EPO; JPO;	
		and (self-test control device)) and (714/733.ccls. or 714/734.ccls.	DERWENT;	
		or 714/724.ccls. or 714/30.ccls. or 714/726.ccls. )) and error\$1)	IBM_TDB	
20	1257016	and ("BIST" or "built-in self-test")	LICDATE	2004/06/06 47 04
20	1257816	built-in self-test controller\$1	USPAT; US-PGPUB;	2004/06/26 17:24
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
21	86	11111111	USPAT;	2004/06/26 17:24
		testing device)) and ((evaluat\$3 and (test result\$1)) and (reading out result\$1 and (external testing device)))) and (test result	US-PGPUB; EPO; JPO;	
	ļ	memory)) and (self-test control device)) and (714/733.ccls. or	DERWENT;	
		714/734.ccls. or 714/724.ccls. or 714/30.ccls. or 714/726.ccls. ))	IBM_TDB	
		and error\$1) and ("BIST" or "built-in self-test")) and (built-in		
22	3497997	self-test controller\$1) component\$1	LICDAT.	2004/06/26 17:26
22	) 3757557	componentsi	USPAT; US-PGPUB;	2004/06/26 17:26
			EPO; JPO;	
			DERWENT;	
22			IBM_TDB	
23	54	((((((((((((((((((((((((((((((((((((((	USPAT;	2004/06/26 17:26
		testing device)) and ((evaluat\$3 and (test result\$1)) and (reading out result\$1 and (external testing device)))) and (test result	US-PGPUB; EPO; JPO;	
		memory)) and (self-test control device))) and (714/733.ccls. or	DERWENT;	
		714/734.ccls. or 714/724.ccls. or 714/30.ccls. or 714/726.ccls. ))	IBM_TDB	
		and error\$1) and ("BIST" or "built-in self-test")) and (built-in		
24	354364	self-test controller\$1)) and component\$1 wafer\$!	LICDAT	2004/06/26 17:27
47	+סכדככ	waiciφ:	USPAT; US-PGPUB;	2004/06/26 17:27
			EPO; JPO;	
			DERWENT;	
25	30		IBM_TDB	
25	20	((((((((((((((((((((((((((((((((((((((	USPAT;	2004/06/26 17:28
		out result\$1 and (external testing device)))) and (test result	US-PGPUB; EPO; JPO;	
		memory)) and (self-test control device)) and (714/733.ccls. or	DERWENT;	
		714/734.ccls. or 714/724.ccls. or 714/30.ccls. or 714/726.ccls. ))	IBM_TDB	
i		and error\$1) and ("BIST" or "built-in self-test")) and (built-in		
	L	self-test controller\$1)) and component\$1) and wafer\$!		